

Notice of References Cited	Application/Control No. 10/594,149		Applicant(s)/Patent Under Reexamination SHIMAMURA, TETSURO	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,369,588 A	11-1994	Hayami et al.	340/995.19
*	B	US-5,428,544 A	06-1995	Shyu, Jia-Ming	701/117
*	C	US-5,699,056 A	12-1997	Yoshida, Masato	340/905
*	D	US-6,185,503 B1	02-2001	Sumizawa, Akio	701/209
*	E	US-6,202,024 B1	03-2001	Yokoyama et al.	701/207
*	F	US-6,310,561 B1	10-2001	Nomura et al.	340/905
*	G	US-2001/0034575 A1	10-2001	Takenaga et al.	701/96
*	H	US-2002/0133291 A1	09-2002	Hamada et al.	701/208
*	I	US-2003/0011513 A1	01-2003	Zhao et al.	342/357.09
*	J	US-2003/0152206 A1	08-2003	Kawaguchi et al.	379/201.01
*	K	US-2004/0034464 A1	02-2004	Yoshikawa et al.	701/117
*	L	US-2004/0128066 A1	07-2004	Kudo et al.	701/204
*	M	US-2004/0167710 A1	08-2004	Fushiki et al.	701/208

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0204845 A1	10-2004	Wong, Winnie	701/210
*	B	US-2004/0225437 A1	11-2004	Endo et al.	701/209
*	C	US-6,868,331 B2	03-2005	Hanebrink, Thomas	701/117
*	D	US-2005/0071082 A1	03-2005	Ohmura et al.	701/211
*	E	US-2005/0053310 A1	03-2005	Myochin, Kiyonori	382/284
*	F	US-2005/0190412 A1	09-2005	Noguchi et al.	358/474
*	G	US-2006/0082472 A1	04-2006	Adachi et al.	340/995.13
*	H	US-7,054,713 B2	05-2006	Teng et al.	700/218
*	I	US-2006/0122846 A1	06-2006	Burr et al.	705/001
*	J	US-7,130,402 B2	10-2006	Kawaguchi et al.	379/196
*	K	US-2007/0061723 A1	03-2007	Ohga et al.	715/705
*	L	US-7,246,007 B2	07-2007	Ferman, Martin A.	701/200
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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